

# ITC: International Test Conference 2001 Proceedings October 30-November 1, 2001, Baltimore, MD, USA

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Spyros Tragoudas ECE SIU Paper 18.1. INTERNATIONAL TEST CONFERENCE. 1. 1-4244-1128-9/07/\$25.00 c 2007 IEEE .. BIST," in Proceedings 2004 International Test Conference (ITC 2004), ference 2001, Baltimore, MD, USA, 30 October - 1 November 2001,. ITC : International Test Conference 2001 : proceedings : October 30 . ITC : International Test Conference 2001 : proceedings : October 30-November 1, 2001, Baltimore, MD, USA by International Test Conference (32e : 2001 . Articles in refereed journals Published or accepted - The University . 11. INTERNATIONAL. TEST CONFERENCE. 2001. October 30 – November 1, 2001. Baltimore Convention Center. Baltimore, MD, USA. Conference Theme:. ITC - sigmod Note: At head of title: ITC : International Test Conference 1993 October 17-21, 1993, Convention Center, Baltimore, Maryland, USA--Cover . 8 Book International Test Conference 2001 : proceedings, October 30 - November 1, 2001, Proceedings : International Test Conference 1993 ?????? . 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